

# MECHANICAL CASE OUTLINE

## PACKAGE DIMENSIONS

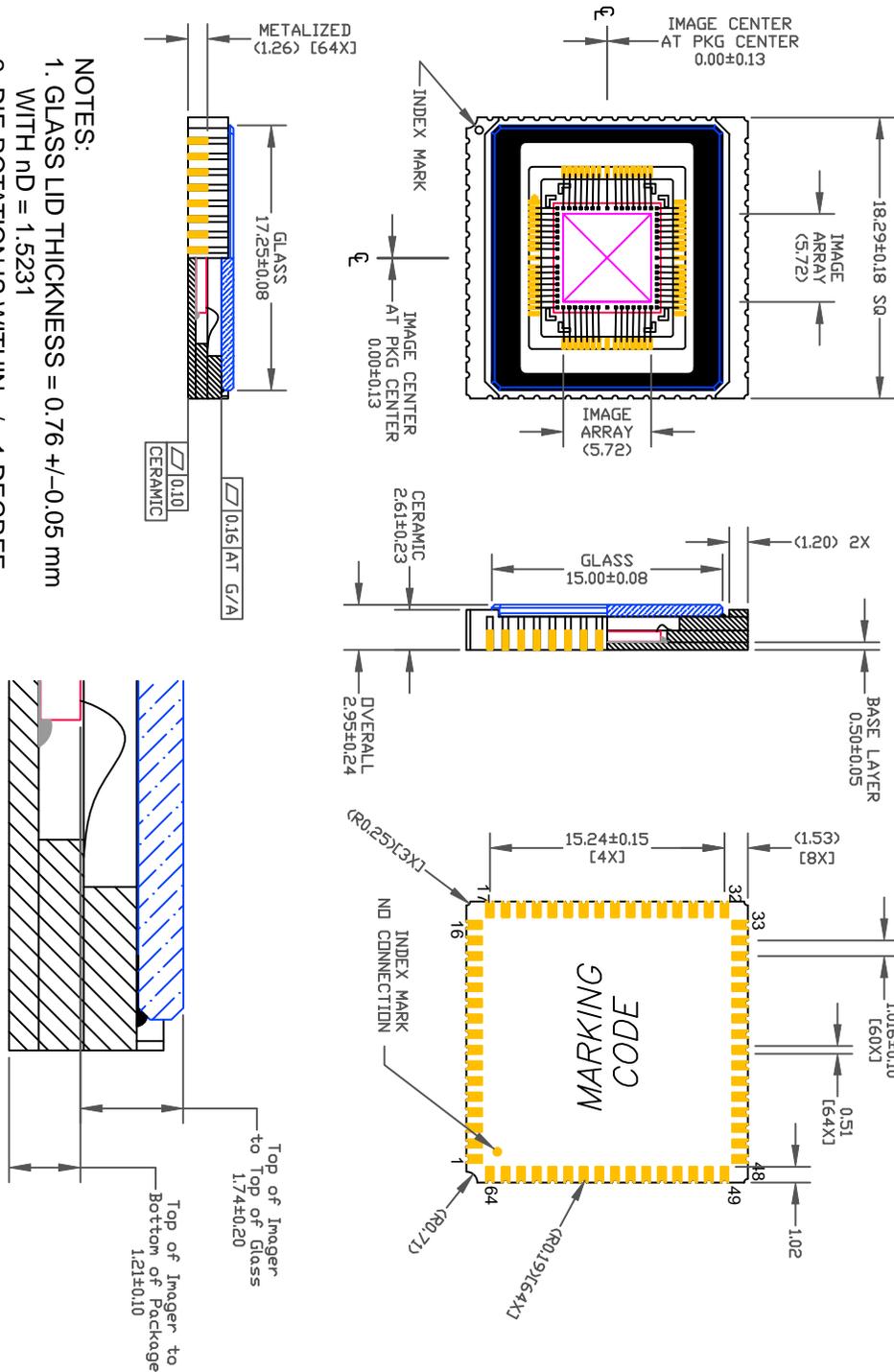
ON Semiconductor®



### CLCC64 18.29x18.29 CASE 848AE ISSUE O

DATE 30 JUL 2014

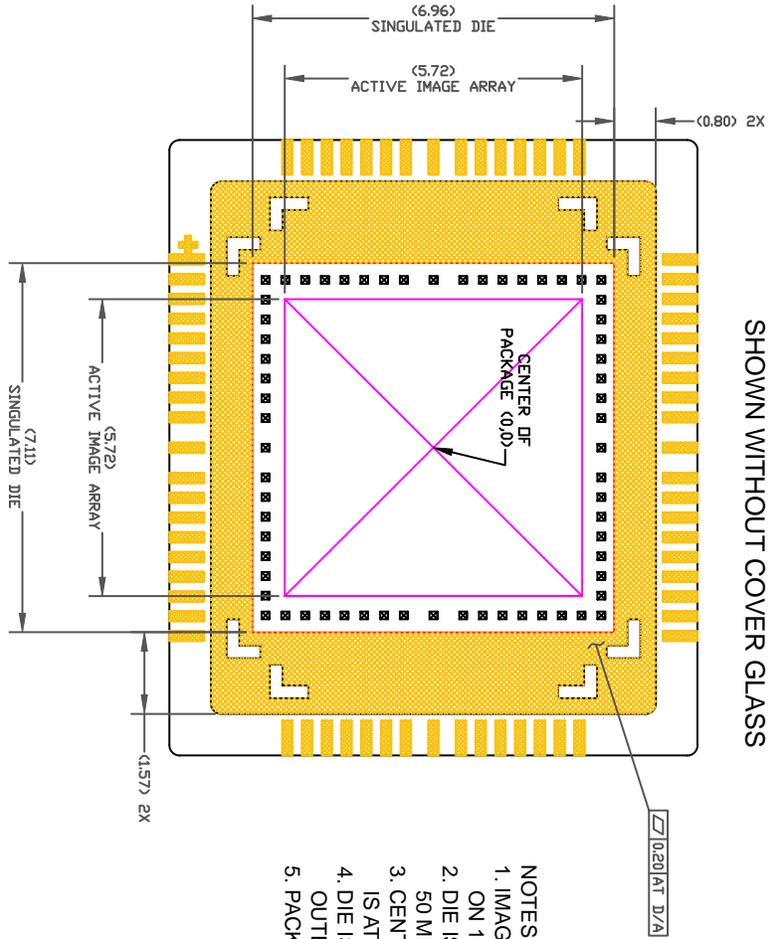
- NOTES:
1. GLASS LID THICKNESS = 0.76 +/- 0.05 mm WITH  $n_d = 1.5231$
  2. DIE ROTATION IS WITHIN +/- 1 DEGREE OF PACKAGE OUTER EDGES.
  3. NO MATERIALS OVERHANG PAST THE OUTER EDGES OF THE CERAMIC PACKAGE.



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- NOTES:
1. IMAGER IS STEPPED (7.16, 7.01) mm ON 150 mm (6") SILICON WAFER.
  2. DIE IS DISPLAYED ASSUMING A 50 MICRON SAW KERF.
  3. CENTER OF ACTIVE IMAGE ARRAY IS AT CENTER OF DIE.
  4. DIE IS CENTERED AND ALIGNED WITHIN OUTER EDGES OF THE CERAMIC PACKAGE.
  5. PACKAGE CAVITY IS CENTERED IN PACKAGE.

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